

P- and N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY							
	V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
N-Channel	40	0.016 at V _{GS} = 10 V	6.7	5.1			
		$0.024 \text{at V} _{GS} = 4.5 \text{V}$	5.8	5.1			
P-Channel	- 40	0.032 at $V_{GS} = -10 \text{ V}$	- 6.1	11.1			
	- 40	0.052 at $V_{GS} = -4.5$ V	- 5.5	11.1			

FEATURES

- DT-Trench Power MOSFET

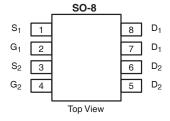
100 % R_g Tested 100 % UIS Tested

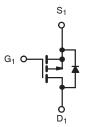


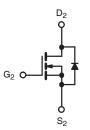
- Backlight Inverter for LCD Display
- Full Bridge Converter











P-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	S T _A = 25 °C, unle	ess otherwi	se noted		
Parameter	Symbol	N-Channel	P-Channel	Unit	
Drain-Source Voltage	V_{DS}	40	- 40	V	
Gate-Source Voltage		V_{GS}	± 20		V
	T _C = 25 °C		6.7	- 6.1	
Continuous Proin Current (T - 150 °C)	T _C = 70 °C] , [5.4	- 4.7	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C		5.6 ^{b, c}	- 4.7 ^{b, c}	
	T _A = 70 °C	1	4.4 ^{b, c}	- 3.7 ^{b, c}	
Pulsed Drain Current		I _{DM}	20	- 20	А
Source-Drain Current Diode Current	T _C = 25 °C	1.	2.5	- 2.5	
	T _A = 25 °C	l _S	1.6 ^{b, c}	- 1.6 ^{b, c}	
Pulsed Source-Drain Current		I _{SM}	20	- 20	
Single Pulse Avalanche Current		I _{AS}	7	- 10	
Single Pulse Avalanche Energy	L = 0 1 mH	E _{AS}	2.45	5	mJ
Maximum Power Dissipation	T _C = 25 °C		3.0	3.1	
	T _C = 70 °C] [1.9	2	\
	T _A = 25 °C	P_{D}	2.0 ^{b, c}	2.0 ^{b, c}	W
	T _A = 70 °C	1	1.25 ^{b, c}	1.25 ^{b, c}	\neg
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55	°C	

THERMAL RESISTANCE RATINGS								
			N-Ch	annel	P-Channel			
Parameter		Symbol	Тур.	Max.	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	54	64	49	62.5	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	33	42	30	40	O/ VV	

Notes:

- a. Based on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 120 $^{\circ}\text{C/W}.$



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Parameter	Symbol	Test Conditions	Min.	Typ. ^a	Max.	Unit		
Static		V _{GS} = 0 V, I _D = 250 μA	N-Ch	30		l		
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	P-Ch	- 30			V	
		I _D = 250 μA	N-Ch	- 30	44			
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA	P-Ch		- 42		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA			- 42			
		II _D = - 250 μA	N-Ch				-	
		$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	P-Ch	1.4	4.6	2.0		
Gate Threshold Voltage	V _{GS(th)}		N-Ch	1.4		3.0	V	
		$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	P-Ch	- 1.2		- 2.5		
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$	N-Ch P-Ch			100 - 100	nA	
		V _{DS} = 30 V, V _{GS} = 0 V	N-Ch			1		
		$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	P-Ch			- 1	-	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$	N-Ch			10	μΑ	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$ $V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$				_		
		20 00	P-Ch	40		- 10		
On-State Drain Current ^b	I _{D(on)}	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	N-Ch	10			Α	
	(,	V _{DS} = -5 V, V _{GS} = -10 V	P-Ch	- 10			ļ	
Drain-Source On-State Resistance ^b	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$	N-Ch		0.016	0.019		
		V _{GS} = - 10 V, I _D = - 3 A	P-Ch		0.032	0.039	Ω	
		$V_{GS} = 4.5 \text{ V}, I_D = 2 \text{ A}$	N-Ch		0.024	0.028		
		$V_{GS} = -4.5 \text{ V}, I_D = -2 \text{ A}$	P-Ch		0.052	0.058		
Forward Transconductance ^b	g _{fs}	V _{DS} = 15 V, I _D = 5 A	N-Ch		22		S	
Toward Hansonidadianoc	015	$V_{DS} = -15 \text{ V}, I_{D} = -5 \text{ A}$	P-Ch		14			
Dynamic ^a								
Input Capacitance	C _{iss}	N Channal	N-Ch		640			
par capacita.ico	-155	N-Channel $V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	P-Ch		970			
Output Capacitance	C _{oss}	103 = 11, 103 = 1,1 1	N-Ch		73		pF	
		P-Channel	P-Ch		120			
Reverse Transfer Capacitance	C _{rss}	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	N-Ch		41		-	
		$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$	P-Ch N-Ch		95	20		
Total Gate Charge	Q_g	$V_{DS} = -20 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -5 \text{ A}$ $V_{DS} = -20 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -5 \text{ A}$	-		11.7	20	-	
		V _{DS} = -20 V, V _{GS} = -10 V, I _D = -3 A	P-Ch		25	38	-	
		N-Channel	N-Ch P-Ch		5.3 11.8	9 18		
	Q _{gs}	$V_{DS} = 20 \text{ V}, V_{GS} = 4.5 \text{ V} I_{D} = 5 \text{ A}$	N-Ch		1.9	10	nC	
Gate-Source Charge		5.01	P-Ch		3.0		-	
	Q _{gd}	P-Channel $V_{DS} = -20 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -5 \text{ A}$	N-Ch		1.7		1	
Gate-Drain Charge		V _{DS} = -20 v, v _{GS} = -4.5 v, I _D = -5 A	P-Ch		5.2		†	
0.1.0		t = 1 MHz	N-Ch	0.5	2.2	4.5	_	
Gate Resistance	R _g		P-Ch	1.0	5.5	11	Ω	



Parameter	Symbol	Test Conditions			Typ. ^a	Max.	Unit
Dynamic ^a							•
Turn-On Delay Time	t _{d(on)}	N.O.	N-Ch		7	14	
Tan Chi Bolay Time	-u(on)	N-Channel $V_{DD} = 20 \text{ V, R}_{L} = 4 \Omega$	P-Ch		7	14	ns
Rise Time	t _r	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_a = 1 \Omega$	N-Ch		10	20	
		- D = 071, 1 GEN 10 1, 1 1g 1 12	P-Ch		12	24	
Turn-Off Delay Time	t _{d(off)}	P-Channel	N-Ch		15	30	
	4(011)	$V_{DD} = -20 \text{ V}, R_L = 4 \Omega$	P-Ch		30	60	
Fall Time	t _f	$I_D \cong$ - 5 A, V_{GEN} = - 10 V, R_g = 1 Ω	N-Ch		9	18	
			P-Ch		9	18	
Turn-On Delay Time	t _{d(on)}	N-Channel	N-Ch		16	30	
	u(on)	$V_{DD} = 20 \text{ V, } R_L = 4 \Omega$	P-Ch		44	80	
Rise Time	t _r	$I_{D} = 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_{g} = 1 \Omega$	N-Ch		17	30	
	'	- 15 = 571, *GEN = 1.5 *, r.g = 1.22	P-Ch		33	50	
Turn-Off Delay Time Fall Time	t _{d(off)}	P-Channel V_{DD} = - 20 V, R_L = 4 Ω $I_D \cong$ - 5 A, V_{GEN} = - 4.5 V, R_g = 1 Ω	N-Ch		16	30	
			P-Ch		28	60	
			N-Ch		10	20	
Tall Tille			P-Ch		13	25	
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	N-Ch			2.5	A
Commission Course Prain Blode Carrein			P-Ch			- 2.5	
Pulse Diode Forward Current ^a	I _{SM}		N-Ch			20	
Tuise Diode Forward Current			P-Ch			- 20	
Pady Diada Valtaga	V _{SD}	I _S = 1.6 A	N-Ch		0.78	1.2	V
Body Diode Voltage		I _S = - 1.6 A	P-Ch		- 0.76	- 1.2	· ·
Dady Diada Dayana Dayana Tima			N-Ch		19	30	
Body Diode Reverse Recovery Time	t _{rr}		P-Ch		26	50	ns
D D: D O	Q _{rr}	N-Channel	N-Ch		14	25	nC
Body Diode Reverse Recovery Charge		$I_F = 2 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$	P-Ch		18.5	35	
Davisias Davisias Fall Time	t _a	P-Channel	N-Ch		13		no
Reverse Recovery Fall Time		$I_F = -2 \text{ A}$, $dI/dt = -100 \text{ A/µs}$, $T_{.1} = 25 \text{ °C}$	P-Ch		12.5		
Dayaraa Daaayary Diaa Tima	t _b	1	N-Ch		6		ns
Reverse Recovery Rise Time			P-Ch		13.5		1

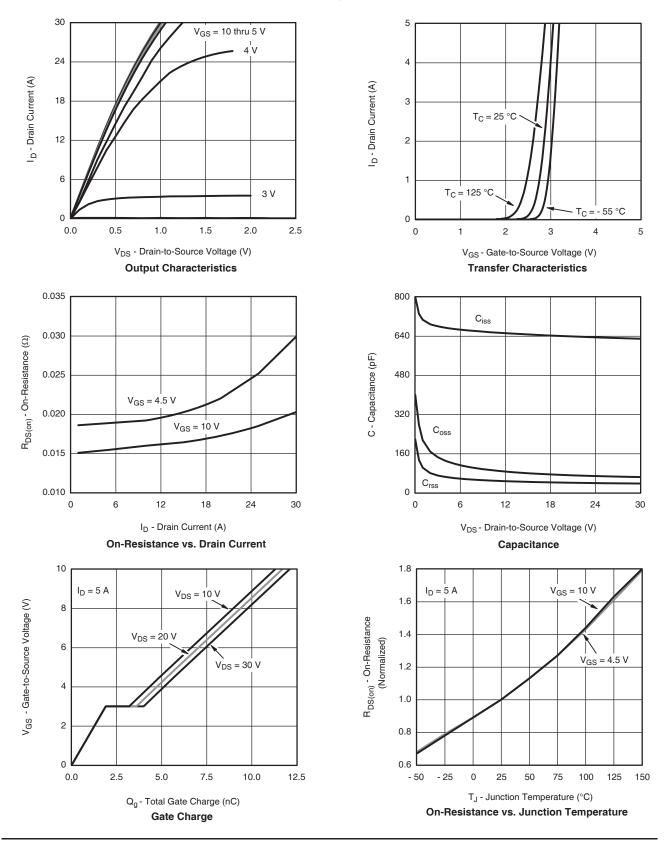
Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Guaranteed by design, not subject to production testing. b. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.

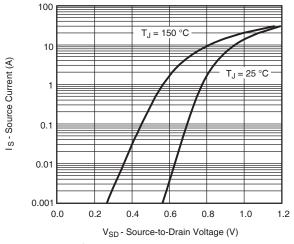


N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

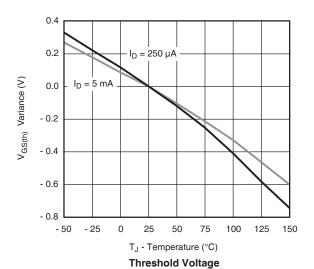




N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Source-Drain Diode Forward Voltage



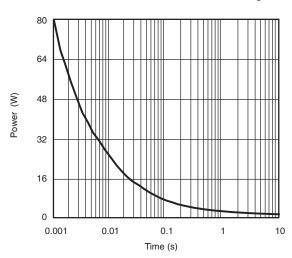
 $I_D = 5 \text{ A}$ 0.16

0.16

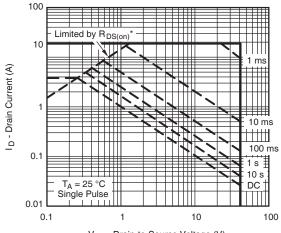
0.12

0.08 $T_A = 125 \, ^{\circ}\text{C}$ 0.04 $T_A = 25 \, ^{\circ}\text{C}$

 $\label{eq:VGS} V_{GS} \mbox{ - Gate-to-Source Voltage (V)} \\$ On-Resistance vs. Gate-to-Source Voltage



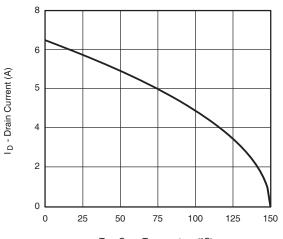
Single Pulse Power, Junction-to-Ambient



 $V_{DS} \text{ - Drain-to-Source Voltage (V)} \\ ^*V_{GS} > \text{ minimum } V_{GS} \text{ at which } r_{DS(on)} \text{ is specified}$

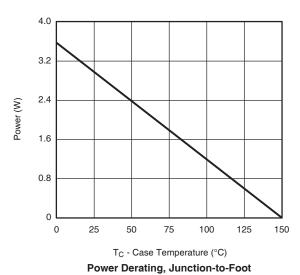
Safe Operating Area, Junction-to-Ambient

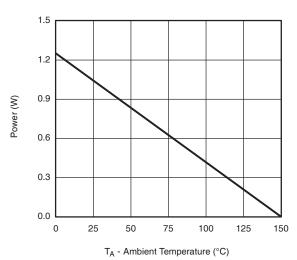
N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



T_C - Case Temperature (°C)

Current Derating*





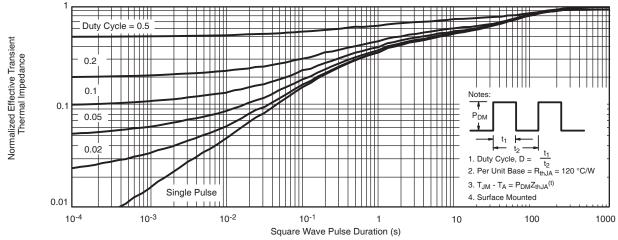
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit

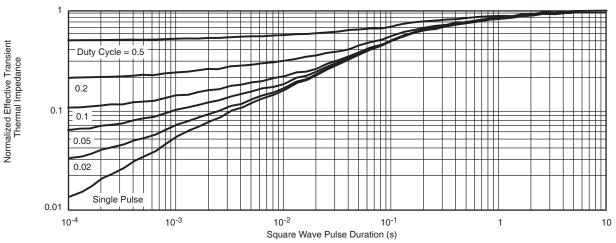


N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



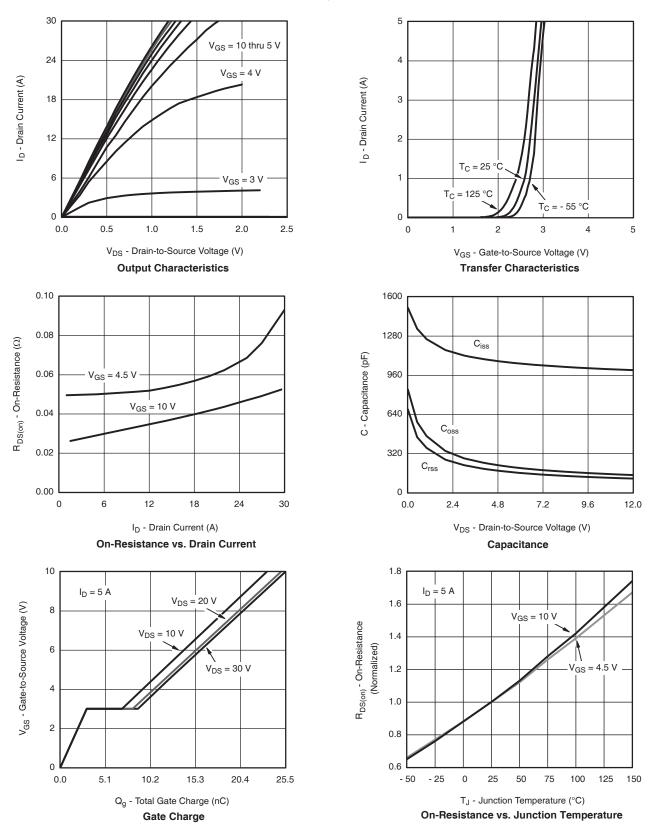


Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





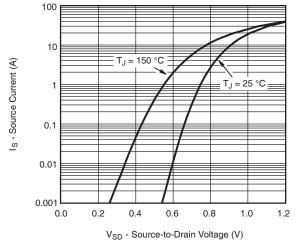
I_D = 5 A

 $T_J = 125$ °C

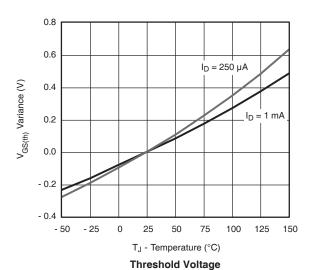
 $T_J = 25$ °C

9 10

P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Source-Drain Diode Forward Voltage



 $\mathsf{R}_{\mathsf{DS}(\mathsf{on})}$ - On-Resistance (Ω) 0.08 0.04 0.00

0.20

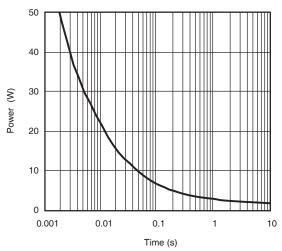
0.16

0.12

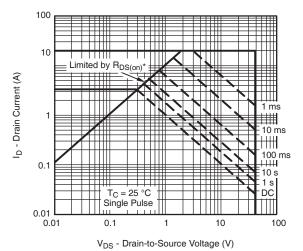
0 1 2 3

5 V_{GS} - Gate-to-Source Voltage (V) On-Resistance vs. Gate-to-Source Voltage

6



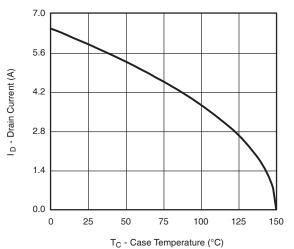
Single Pulse Power, Junction-to-Ambient



* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

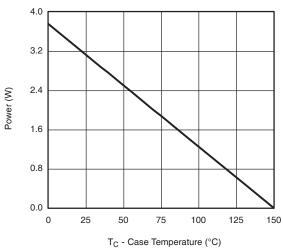
Safe Operating Area, Junction-to-Ambient

P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

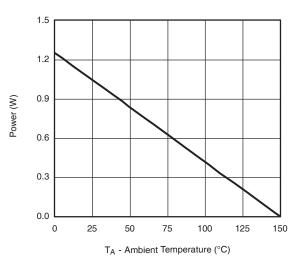


Orange Developer

Current Derating*



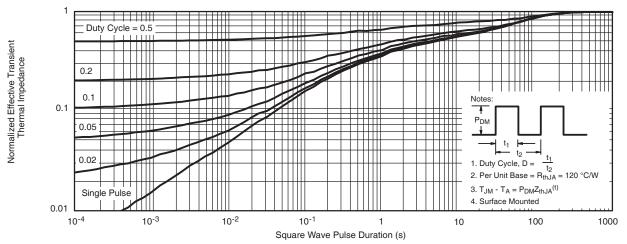
Power Derating, Junction-to-Foot



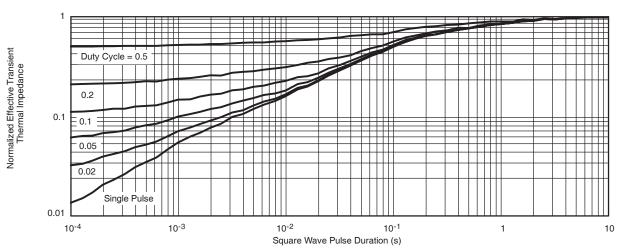
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



Din-Tek SEMICONDUCTOR

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